# 2SK3426

### Silicon N-Channel Junction FET

For impedance conversion in low frequency For electret capacitor microphone

#### Features

- $\bullet$  High mutual conductance  $g_{m}$
- Low noise voltage NV

### PackageCode

- SSSMini3-F1
- Pin Name
  - 1: Drain
  - 2: Source
  - 3: Gate

Absolute Maximum Ratings  $T_a = 25^{\circ}C$ 

Parameter	Symbol	Rating	Unit	
Drain-source voltage (Gate open)	V <sub>DSO</sub>	20	V	
Drain-gate voltage (Source open)	V <sub>DGO</sub>	20	V	
Drain-source current (Gate open)	I <sub>DSO</sub>	2	mA	
Drain-gate current (Source open)	I <sub>DGO</sub>	2	mA	
Gate-source current (Drain open)	I <sub>GSO</sub>	2	mA	
Power dissipation	P <sub>D</sub>	100	mW	
Operating ambient temperature	T <sub>opr</sub>	-20 to +80	°C	
Storage temperature	T <sub>stg</sub>	-55 to +125	°C	

Marking Symbol: 4E

#### **Electrical Characteristics** $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain current *1	ID	$V_{DS} = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$	100	-0/1-	460	μΑ
Drain-source current	I <sub>DSS</sub>	$V_{DS} = 2.0 V, R_D = 2.2 k\Omega \pm 1\%, V_{GS} = 0$	107	22	470	μΑ
Mutual conductance	gm	$V_D = 2.0 V, V_{GS} = 0, f = 1 kHz$	660	1 600		μS
Noise voltage	♡ NV	$V_D = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, \text{ A-Curve}$	<u> </u>		10	μV
Voltage gain	G <sub>V1</sub>	$V_D = 2.0 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, e_G = 10 mV, f = 1 kHz$	-7.5	-4.7		dB
	G <sub>V2</sub>	$V_D = 12 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, e_G = 10 mV, f = 1 kHz$	-4.0	-1.5		
	G <sub>V3</sub>	$V_D = 1.5 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, e_G = 10 mV, f = 1 kHz$	-8.0	-5.0		
	$\Delta  G_V.f ^{*2}$	$V_{\rm D} = 2.0 \text{ V}, R_{\rm D} = 2.2 \text{ k}\Omega \pm 1\%$ $C_{\rm O} = 5 \text{ pF}, e_{\rm G} = 10 \text{ mV}, \text{ f} = 1 \text{ kHz to 70 Hz}$		0	1.7	
Voltage gain difference	$ G_{V2} - G_{V1} $		0		4.0	dB
	G <sub>V1</sub> - G <sub>V3</sub>		0		1.7	

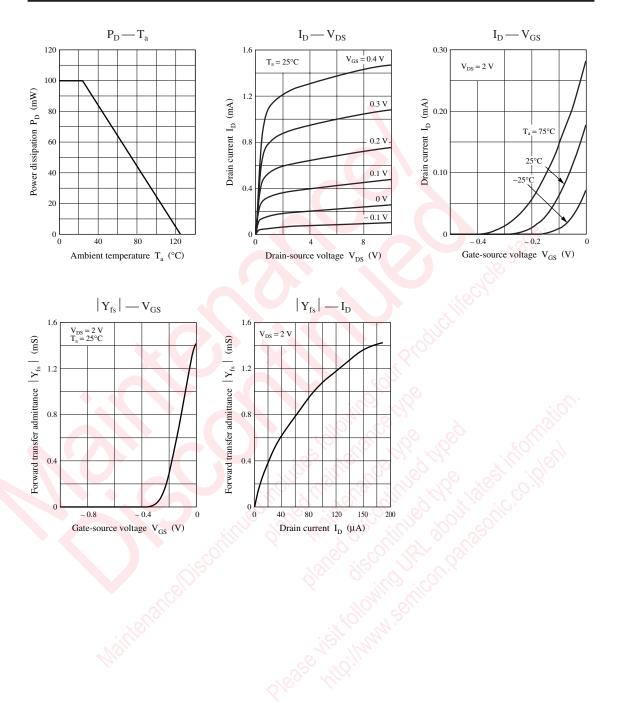
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*1:  $I_{\text{D}}$  is assured for  $I_{\text{DSS}}.$ 

\*2:  $\Delta$  | G<sub>V</sub>. f | is assured for AQL 0.065%. (The measurement method is used by source-grounded circuit.)

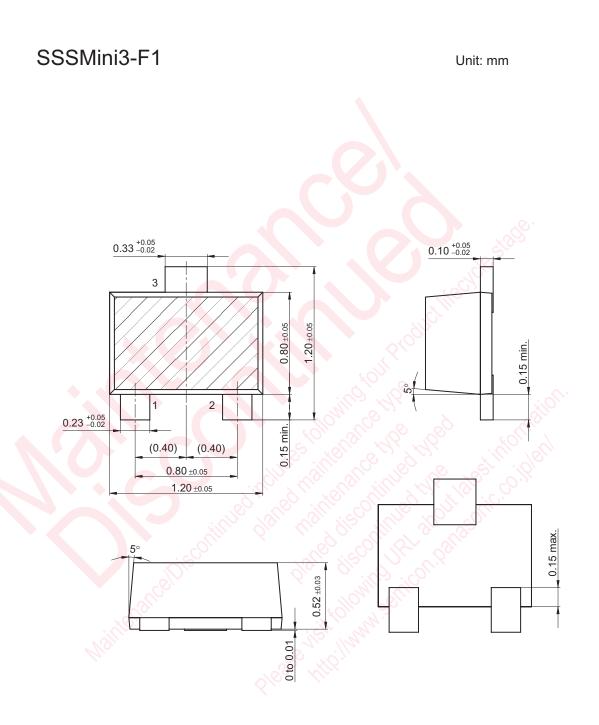
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